

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/708,242	LIU ET AL.	
Examiner	Art Unit	
Gonal C Ray	2111	

SEARCHED					
Class	Subclass	Date	Examiner		
710	240,74,30 0,316,3,36 ,38,314,31 5	7/24/2007	GCR		
710	8	7/24/2007	GCR		
711	112,162	7/24/2007	GCR		
711	151,114	7/24/2007	GCR		
711	154,203	7/24/2007	GCR		
714	5,6,43	7/24/2007	GCR		
370	351,431	7/24/2007	GCR		
370	464,906	7/24/2007	GCR		
370	910,228	7/24/2007	GCR		
370	386	7/24/2007	GCR		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	77-			
see interfer	text search - ence search tout	7/24/2007	GCR	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	7/24/2007	GCR		
EAST: USPT (see search history printouts)	7/24/2007	GCR		
NPL: IEEE Xplore (see search history printouts)	7/24/2007	GCR		
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